

transmission electron microscopy (TEM)

Any technique in which an electron transparent sample is bombarded with an electron beam and the intensity of the transmitted electrons which is determined by scattering phenomena (electron absorption phenomena) in the interior of the sample is recorded. TEM essentially provides a high resolution image of the microstructure of a thin sample. This technique is often just called electron microscopy. The term transmission electron microscopy is however recommended for the sake of a clear distinction from other electron microscopic techniques.

Source:

PAC, 1983, 55, 2023 (*Nomenclature, symbols and units recommended for in situ microanalysis (Provisional)*) on page 2024